

Notice of References Cited	Application/Control No. 09/922,065	Applicant(s)/Patent Under Reexamination MAR ET AL.	
	Examiner Ted M. Wang	Art Unit 2634	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Phase Noise Measurements with Spectrum Analyzers of the FSE family, Application Note 1EPAN 16E, 02 Oct. 95, Josef Wolf
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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